

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/759,630	BOEMMEL ET AL.
Examiner	Art Unit	
Hae M. Hyeon	2839	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
439	495	10/05	hmh
439	590		
439	937		